

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/049,373	ISHIDA ET AL.	
Examiner	Art Unit	<del></del> -
Thaian N. Ton	1632	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated Search	3/13/2006	TNT
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